

V_{DRM} = 2800 V
 $I_{T(AV)M}$ = 3740 A
 $I_{T(RMS)}$ = 5880 A
 I_{TSM} = 60×10^3 A
 V_{TO} = 0.95 V
 r_T = 0.1 mW

Phase Control Thyristor

5STP 33L2800

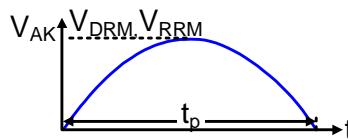
Doc. No. 5SYA1011-04 May 07

- Patented free-floating silicon technology
- Low on-state and switching losses
- Designed for traction, energy and industrial applications
- Optimum power handling capability
- Interdigitated amplifying gate

Blocking

Maximum rated values ¹⁾

Parameter	Symbol	Conditions	5STP 33L2800		Unit
Max repetitive peak forward and reverse blocking voltage	V_{DRM} , V_{RRM}	$f = 50$ Hz, $t_p = 10$ ms, $T_{vj} = 5 \dots 125^\circ\text{C}$, Note 1	2800		V
Critical rate of rise of commutating voltage	dv/dt_{crit}	Exp. to 1880 V, $T_{vj} = 125^\circ\text{C}$	1000		V/ μ s



Characteristic values

Parameter	Symbol	Conditions	min	typ	max	Unit
Forward leakage current	I_{DRM}	V_{DRM} , $T_{vj} = 125^\circ\text{C}$			400	mA
Reverse leakage current	I_{RRM}	V_{RRM} , $T_{vj} = 125^\circ\text{C}$			400	mA

Note 1: Voltage de-rating factor of 0.11% per $^\circ\text{C}$ is applicable for T_{vj} below $+5^\circ\text{C}$

Mechanical data

Maximum rated values ¹⁾

Parameter	Symbol	Conditions	min	typ	max	Unit
Mounting force	F_M		63	70	84	kN
Acceleration	a	Device unclamped			50	m/s^2
Acceleration	a	Device clamped			100	m/s^2

Characteristic values

Parameter	Symbol	Conditions	min	typ	max	Unit
Weight	m				1.45	kg
Housing thickness	H	$F_M = 70$ kN, $T_a = 25^\circ\text{C}$	25.8		26.4	mm
Surface creepage distance	D_s		36			mm
Air strike distance	D_a		15			mm

1) Maximum rated values indicate limits beyond which damage to the device may occur

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On-state

Maximum rated values ¹⁾

Parameter	Symbol	Conditions	min	typ	max	Unit
Average on-state current	$I_{T(AV)M}$	Half sine wave, $T_c = 70^\circ C$			3740	A
RMS on-state current	$I_{T(RMS)}$				5880	A
Peak non-repetitive surge current	I_{TSM}	$t_p = 10 \text{ ms}, T_{vj} = 125^\circ C, \text{sine wave}$ $\text{after surge: } V_D = V_R = 0 \text{ V}$			60×10^3	A
Limiting load integral	I^2t				18×10^6	$A^2\text{s}$
Peak non-repetitive surge current	I_{TSM}	$t_p = 8.3 \text{ ms}, T_{vj} = 125^\circ C, \text{sine wave}$ $\text{after surge: } V_D = V_R = 0 \text{ V}$			65×10^3	A
Limiting load integral	I^2t				17.5×10^6	$A^2\text{s}$

Characteristic values

Parameter	Symbol	Conditions	min	typ	max	Unit
On-state voltage	V_T	$I_T = 3000 \text{ A}, T_{vj} = 125^\circ C$			1.23	V
Threshold voltage	$V_{(TO)}$	$I_T = 2000 \text{ A} - 6000 \text{ A}, T_{vj} = 125^\circ C$			0.95	V
Slope resistance	r_T				0.1	$m\Omega$
Holding current	I_H	$T_{vj} = 25^\circ C$ $T_{vj} = 125^\circ C$			100	mA
Latching current	I_L				60	mA
		$T_{vj} = 25^\circ C$ $T_{vj} = 125^\circ C$			500	mA
					300	mA

Switching

Maximum rated values ¹⁾

Parameter	Symbol	Conditions	min	typ	max	Unit
Critical rate of rise of on-state current	di/dt_{crit}	$T_{vj} = 125^\circ C,$ $I_T = I_{T(AV)},$ $f = 50 \text{ Hz}$			250	$A/\mu s$
Critical rate of rise of on-state current	di/dt_{crit}				1000	$A/\mu s$
Circuit-commutated turn-off time	t_q	$T_{vj} = 125^\circ C, I_{TRM} = 2000 \text{ A},$ $V_R = 200 \text{ V}, di_T/dt = -1.5 \text{ A}/\mu s,$ $V_D \leq 0.67 \cdot V_{DRM}, dv_D/dt = 20 \text{ V}/\mu s$	400			μs

Characteristic values

Parameter	Symbol	Conditions	min	typ	max	Unit
Reverse recovery charge	Q_{rr}	$T_{vj} = 125^\circ C, I_{TRM} = 2000 \text{ A},$ $V_R = 200 \text{ V},$ $di_T/dt = -1.5 \text{ A}/\mu s$	1000		2200	μAs
Reverse recovery current	I_{RM}		35		55	A
Gate turn-on delay time	t_{gd}	$T_{vj} = 25^\circ C, V_D = 0.4 \cdot V_{RM}, I_{FG} = 2 \text{ A},$ $t_r = 0.5 \mu s$			3	μs

Triggering

Maximum rated values¹⁾

Parameter	Symbol	Conditions	min	typ	max	Unit
Peak forward gate voltage	V_{FGM}				12	V
Peak forward gate current	I_{FGM}				10	A
Peak reverse gate voltage	V_{RGM}				10	V
Average gate power loss	$P_{G(AV)}$		see Fig. 9			W

Characteristic values

Parameter	Symbol	Conditions	min	typ	max	Unit
Gate-trigger voltage	V_{GT}	$T_{vj} = 25^\circ C$			2.6	V
Gate-trigger current	I_{GT}	$T_{vj} = 25^\circ C$			400	mA
Gate non-trigger voltage	V_{GD}	$V_D = 0.4 \times V_{DRM}, T_{vjmax} = 125^\circ C$	0.3			V
Gate non-trigger current	I_{GD}	$V_D = 0.4 \times V_{DRM}, T_{vjmax} = 125^\circ C$	10			mA

Thermal

Maximum rated values¹⁾

Parameter	Symbol	Conditions	min	typ	max	Unit
Operating junction temperature range	T_{vj}				125	°C
Storage temperature range	T_{stg}		-40		140	°C

Characteristic values

Parameter	Symbol	Conditions	min	typ	max	Unit
Thermal resistance junction to case	$R_{th(j-c)}$	Double-side cooled $F_m = 63...84$ kN			7	K/kW
	$R_{th(j-c)A}$	Anode-side cooled $F_m = 63...84$ kN			14	K/kW
	$R_{th(j-c)C}$	Cathode-side cooled $F_m = 63...84$ kN			14	K/kW
Thermal resistance case to heatsink	$R_{th(c-h)}$	Double-side cooled $F_m = 63...84$ kN			1.5	K/kW
	$R_{th(c-h)}$	Single-side cooled $F_m = 63...84$ kN			3	K/kW

Analytical function for transient thermal impedance:

$$Z_{th(j-c)}(t) = \sum_{i=1}^n R_i (1 - e^{-t/\tau_i})$$

i	1	2	3	4
$R_i(K/kW)$	4.700	0.853	1.070	0.490
$\tau_i(s)$	0.4787	0.0824	0.0104	0.0041

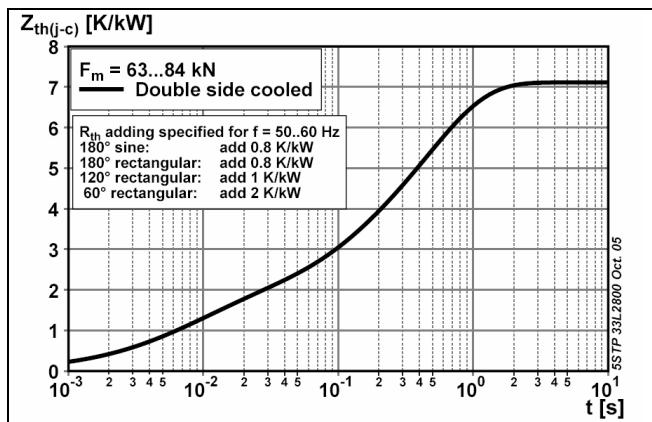


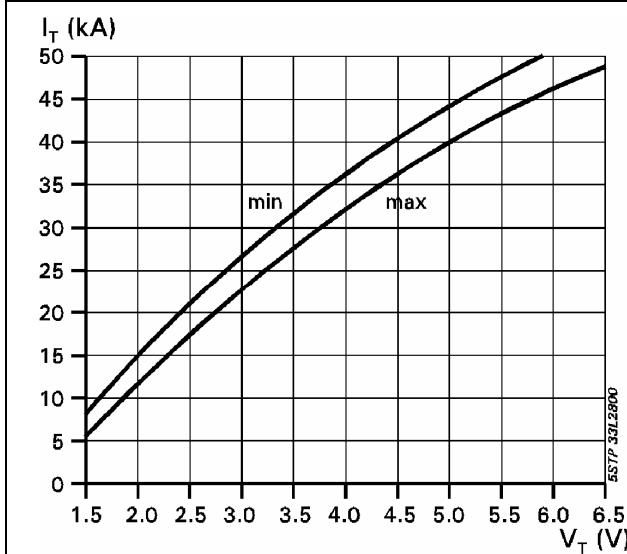
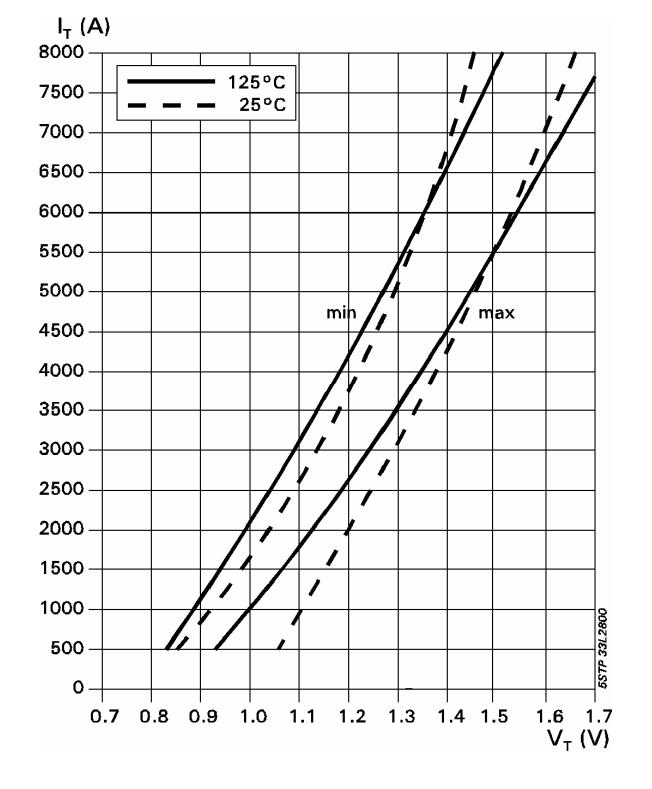
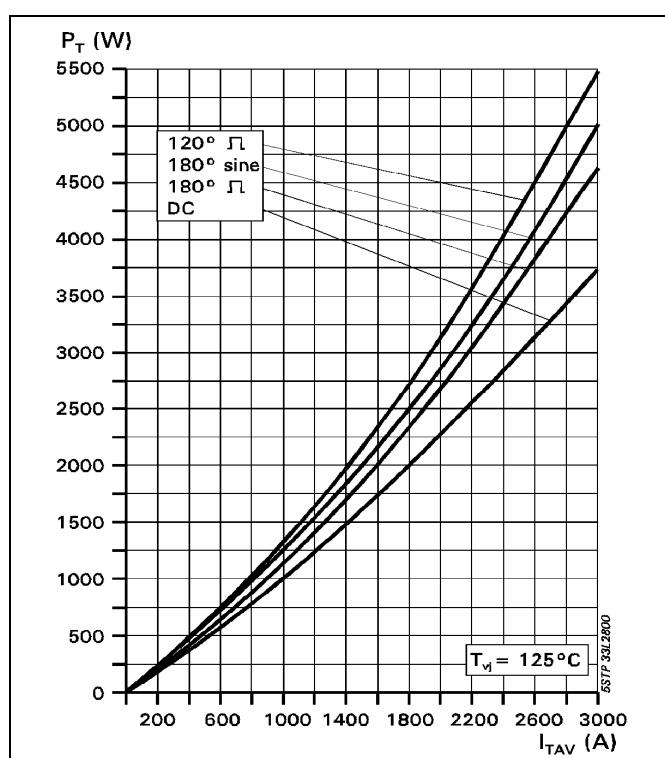
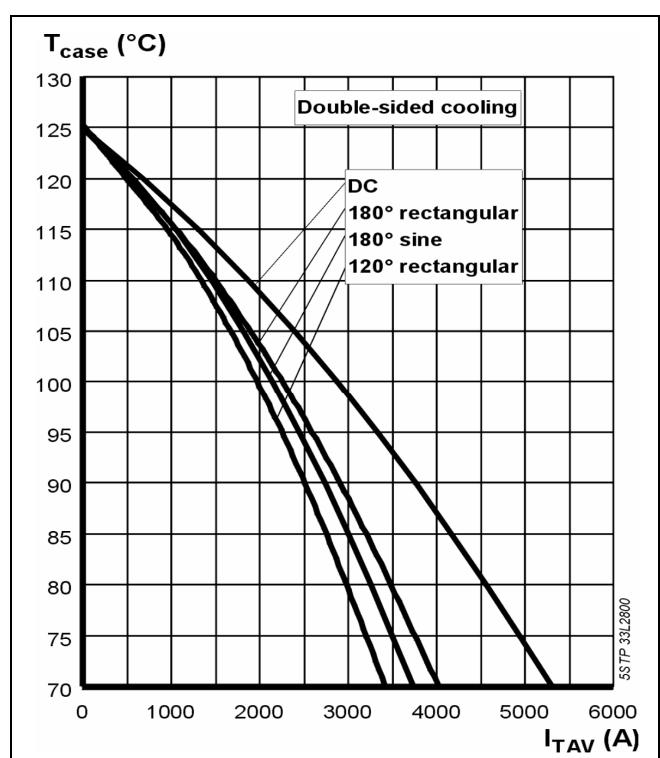
Fig. 1 Transient thermal impedance (junction-to-case) vs. time

On-state characteristic model:

$$V_{T\max} = A + B \cdot I_T + C \cdot \ln(I_T + 1) + D \cdot \sqrt{I_T}$$

Valid for $i_T = 400 - 11000$ A

A	B	C	D
731.2×10^{-3}	79.0×10^{-6}	17.9×10^{-3}	2.314×10^{-3}

**Fig. 2** On-state characteristics, $T_j=125^\circ\text{C}$, 10ms half sine**Fig. 3** On-state voltage characteristics**Fig. 4** On-state power dissipation vs. mean on-state current, turn-on losses excluded**Fig. 5** Max. permissible case temperature vs. mean on-state current, switching losses ignored

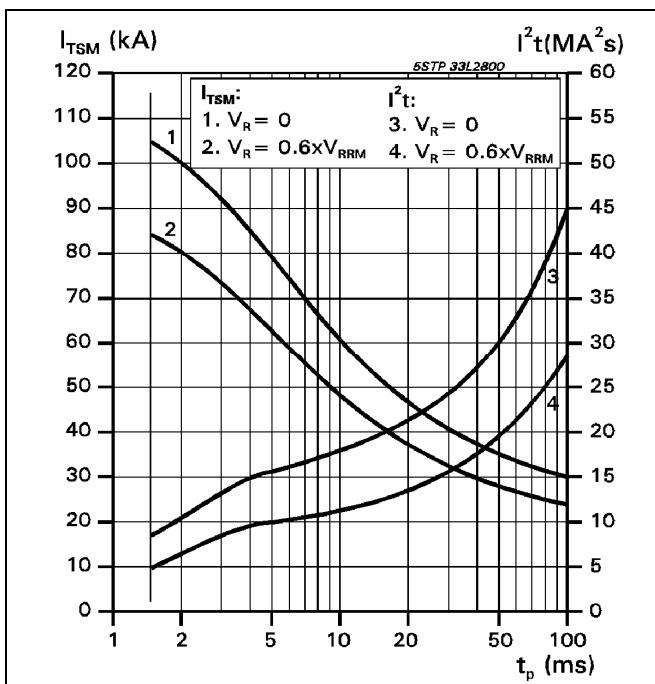


Fig. 6 Surge on-state current vs. pulse length, half-sine wave

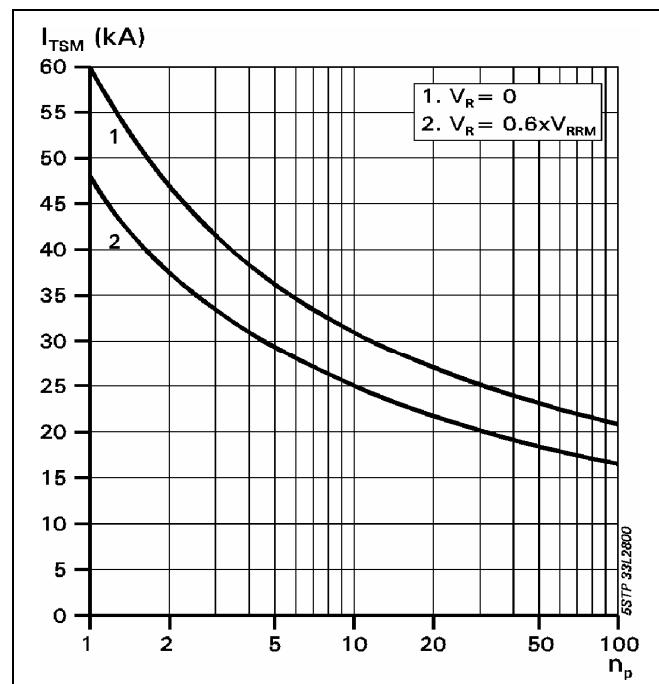


Fig. 7 Surge on-state current vs. number of pulses, half-sine wave, 10 ms, 50Hz

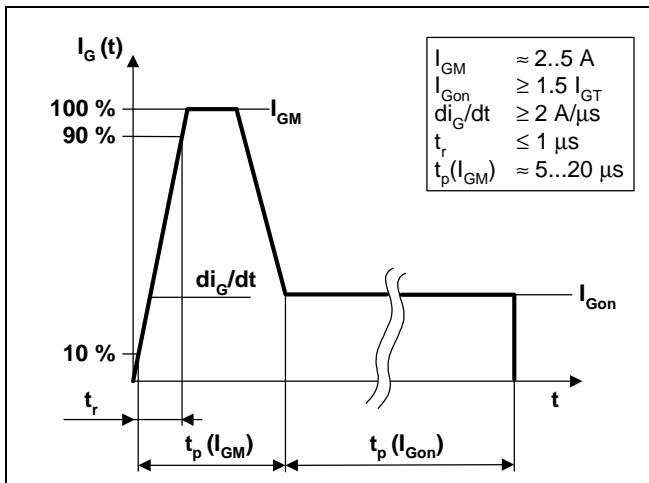


Fig. 8 Recommended gate current waveform

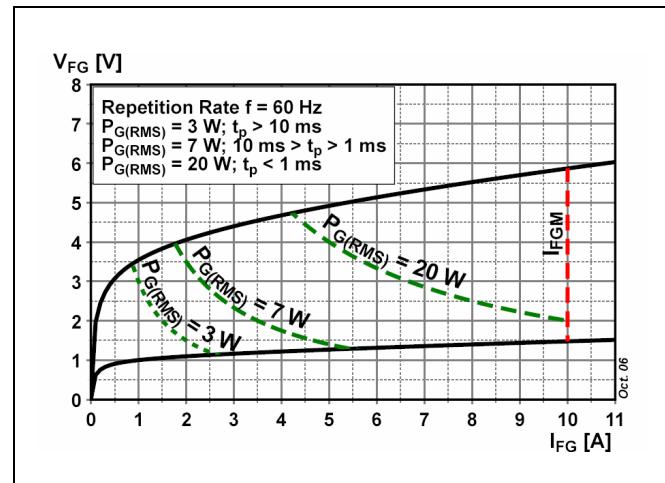


Fig. 9 Max. peak gate power loss

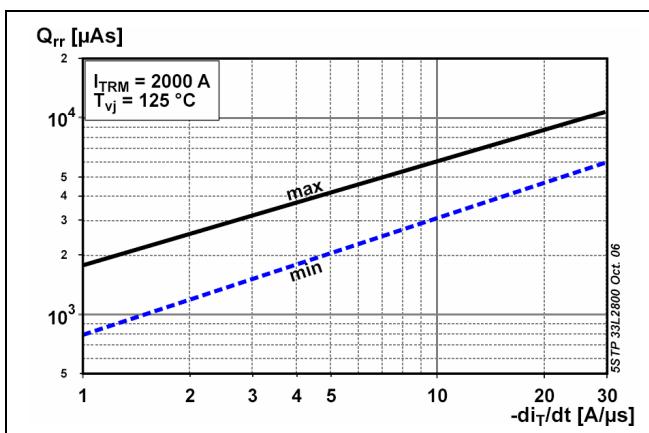


Fig. 10 Reverse recovery charge vs. decay rate of on-state current

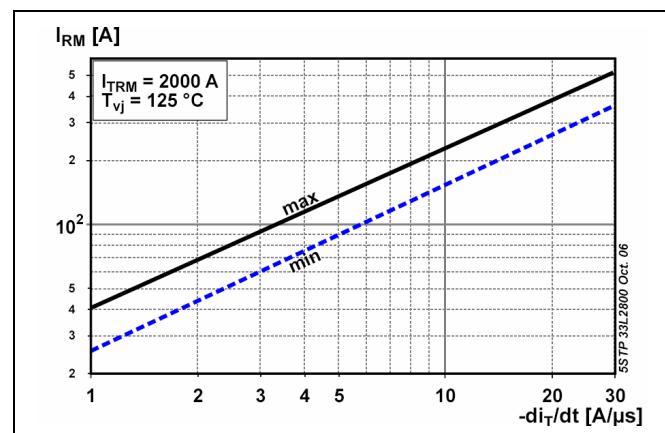
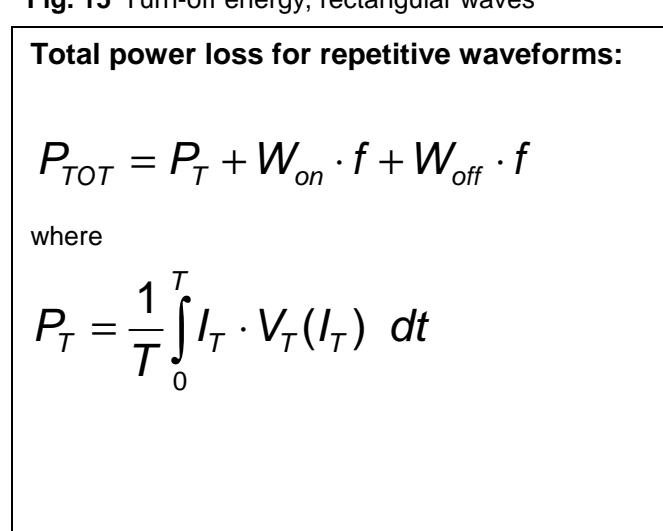
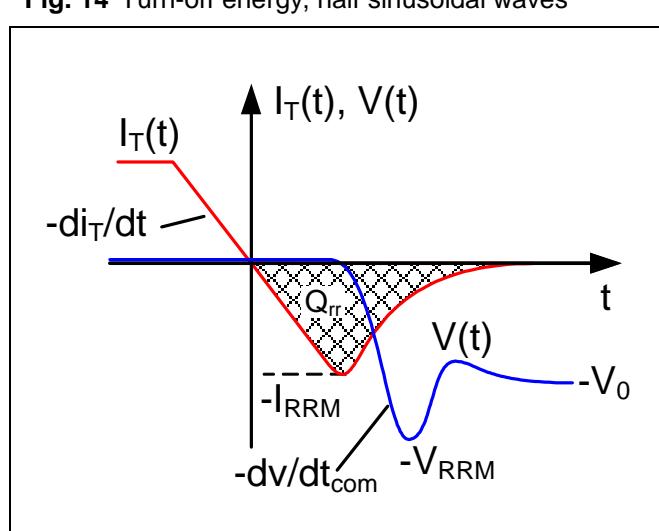
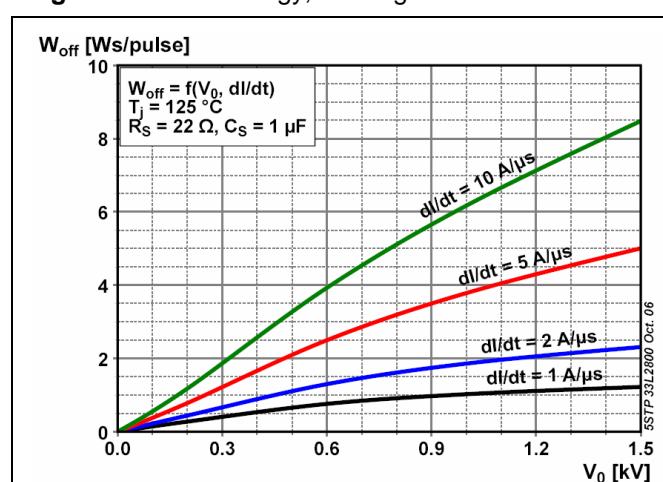
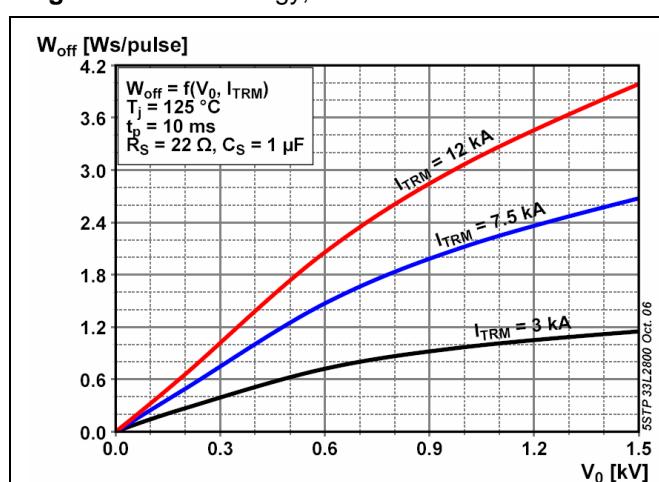
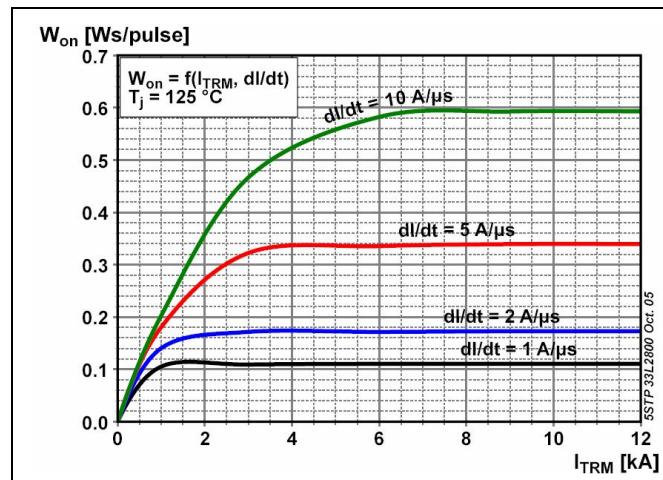
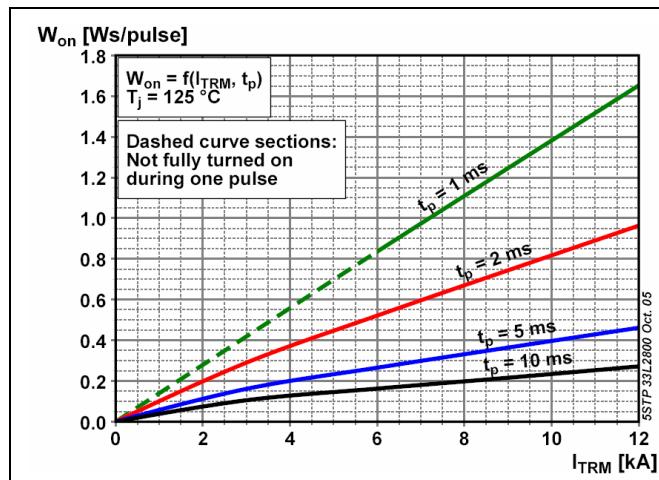


Fig. 11 Peak reverse recovery current vs. decay rate of on-state current

Turn-on and Turn-off losses



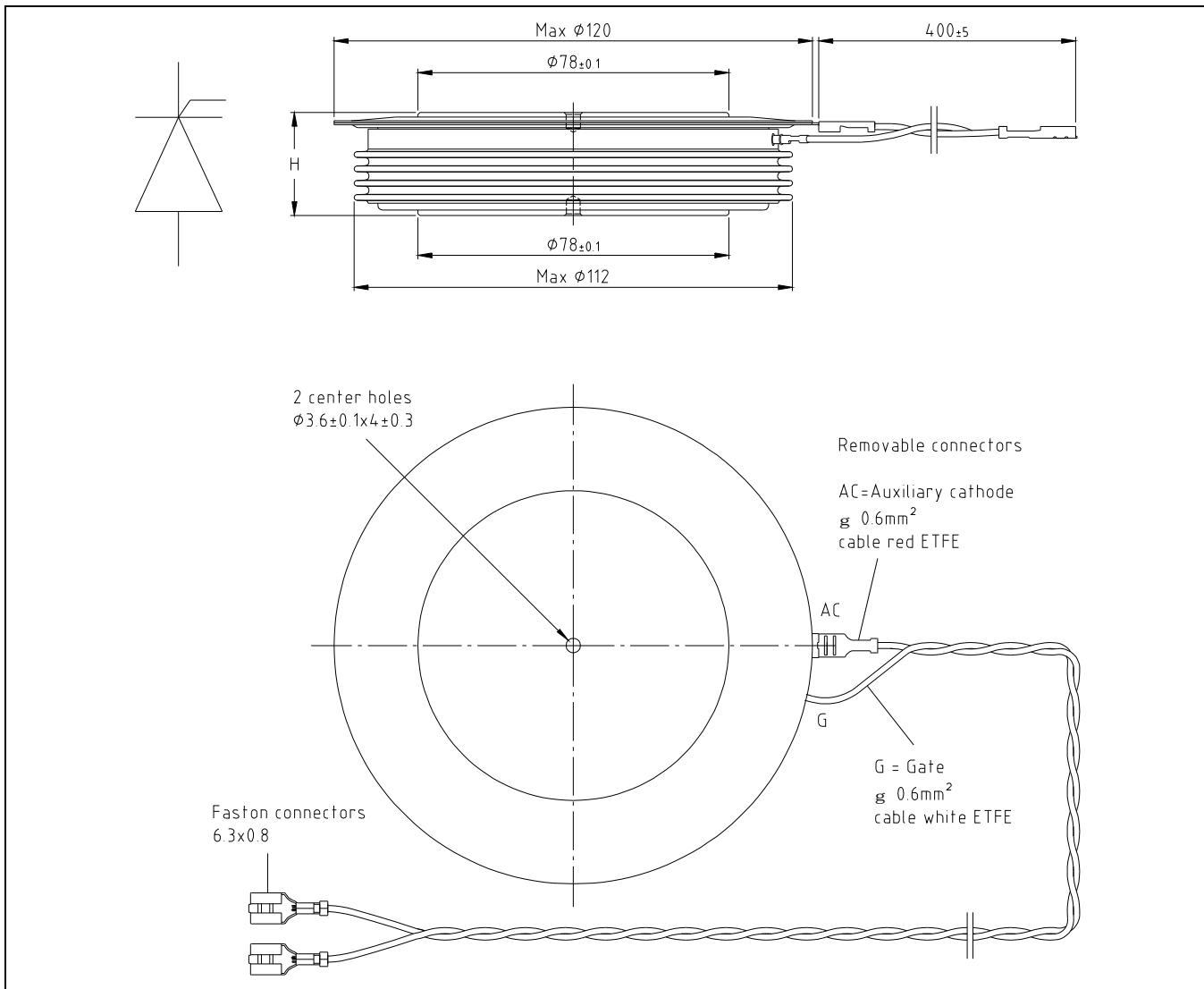


Fig. 18 Device Outline Drawing

Related documents:

- 5SYA 2020 Design of RC-Snubber for Phase Control Applications
- 5SYA 2049 Voltage definitions for phase control thyristors and diodes
- 5SYA 2051 Voltage ratings of high power semiconductors
- 5SYA 2034 Gate-Drive Recommendations for PCT's
- 5SYA 2036 Recommendations regarding mechanical clamping of Press Pack High Power Semiconductors
- 5SZK 9104 Specification of environmental class for pressure contact diodes, PCTs and GTO, STORAGE available on request, please contact factory
- 5SZK 9105 Specification of environmental class for pressure contact diodes, PCTs and GTO, TRANSPORTATION available on request, please contact factory

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